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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/075,840	02/13/2002	Ken Anderson	495812001400	9040
75	90 06/22/2004		EXAM	INER
Robert E. Sche	eid		JUBA JR	, JOHN
Morrison & Foe	erster LLP			
425 Market Street			ART UNIT	PAPER NUMBER
San Francisco, CA 94105-2482			2872	

DATE MAILED: 06/22/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)	
	10/075,840	ANDERSON, KEN	
Office Action Summary	Examin r	Art Unit	
	John Juba, Jr.	2872	
The MAILING DATE of this communication a Period for Reply	ppears on the cover sheet wi	th th correspondenc addr	ss
A SHORTENED STATUTORY PERIOD FOR REF THE MAILING DATE OF THIS COMMUNICATION - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above, the maximum statutory perio - Failure to reply within the set or extended period for reply will, by stat Any reply received by the Office later than three months after the mai earned patent term adjustment. See 37 CFR 1.704(b).	N. 1.136(a). In no event, however, may a reply within the statutory minimum of third will apply and will expire SIX (6) MON ute, cause the application to become AB	eply be timely filed y (30) days will be considered timely. THS from the mailing date of this comm	nunication.
Status			
1) Responsive to communication(s) filed on 31	March 2004.		
<u> </u>	nis action is non-final.		
3) Since this application is in condition for allow closed in accordance with the practice unde			ierits is
Disposition of Claims			
4)	rawn from consideration. 59 is/are rejected. 52-58, 60, 61 is/are objected	i to.	
Application Papers			
9)☐ The specification is objected to by the Exami			
10) ☐ The drawing(s) filed on is/are: a) ☐ a			
Applicant may not request that any objection to the			4.4047.11
Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the			
Priority under 35 U.S.C. § 119			
12) Acknowledgment is made of a claim for forei a) All b) Some * c) None of: 1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the priority docume application from the International Bure * See the attached detailed Office action for a li	ents have been received. ents have been received in A riority documents have been eau (PCT Rule 17.2(a)).	pplication No received in this National St	age
Attachment(s)	∧ □ 1-1	Nummany (DTO 442)	
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) 	Paper No(Summary (PTO-413) s)/Mail Date	
Information Disclosure Statement(s)-(PTO-1449 or PTO/SB/0 Paper No(s)/Mail Date	(D8) 5) ☐ Notice of I 6) ☐ Other:	nformal Patent Application (PTO-1) 	52)

DETAILED ACTION

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

Claims 1, 5, 6, 8, 12, 13, 37, 38, 46, 49, 50, 51, and 59 are rejected under 35 U.S.C. 102(a) as being anticipated by FUJI XEROX (JP 2000-268380 A). Referring primarily to Figure 3 and the associated text of the attached machine translation, disclose a hologram recording apparatus comprising polarizing beam splitter in the output arm of the object beam and a detector. The basic operation is described in paragraph [0019]. A first image, containing an alignment pattern is recorded using a Ppolarized alignment (object) beam and a P-polarized reference beam that interfere to form an amplitude-type hologram containing an alignment image. A second hologram is multiplexed in the same region using a P-polarized data (object) and an S-polarized reference beam that interfere to form a polarization-modulating hologram containing data. Due to the presence of the first, alignment hologram, the output arm of the data beam contains (in addition to 0-order P-polarized data) S-polarized light diffracted by the alignment hologram (see paras. [0044] - [0047]). During the second write operation, the S-polarized alignment pattern may be regarded as an "offset" component of the output arm of the data beam. Since FUJI XEROX disclose a control circuit responsive

to the detected alignment pattern to position the optical head, the detector (53s) must be regarded as being "for" (capable of) measuring the offset component.

With regard to claims 37, 50, and their respective dependent claims, the offset component "characterizes" a difference between the (P) polarization of the first component of the source beam and the (S) polarization of the second component of the source beam, in that during recording of the second, polarization-modulated hologram, the offset beam contains as (S polarized light) reference light diffracted by the amplitude-type alignment pattern, and no contribution from the P-polarized data beam. If the offset component contains contributions other than from the intensity modulated alignment pattern, then, the first component of the source beam is not orthogonal to the second component of the source beam.

With regard to claims 6 and 38, the act of passing the source beam through splitter (24) may be regarded as "adjusting" the polarization, since light containing a single polarization is derived from light having a different polarization orientation.

With regard to claims 8 and 50, the apparatus comprises a laser (21); a beam splitter (24) for splitting the source into two components (2) and (3); a data-beam source (26) for generating a data beam (4) having a first (P) polarization; a reference beam source (28) for generating a reference beam by adjusting the second component (3) of the source beam to have a second polarization (6)(P/S); a holographic medium (10); a polarization beam splitter (52) for separating an offset component (alignment image) from the output arm (7) of the data beam; and a detector (53s) for measuring the offset component.

With regard to claims 13 and 51, FUJI XEROX disclose the data beam source (26) as suitably being a liquid crystal display panel. It will be appreciated that liquid crystal panels "adjust" the polarization of light passing therethrough.

With regard to claims 46 and 59, an output power unit and measurement inheres among the detector (53s) and control circuit 70 of FUJI XEROX, since the intensity of the diffracted alignment pattern must be detected before a determination respecting alignment can be made. Thus, FUJI XEROX monitor power within the specificity recited in these newly presented claims.

Allowable Subject Matter

Claims 2 - 4, 7, 9 - 11, 14, 36, 39 - 45, 47, 48, 52 - 58, 60 and 61 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The following is a statement of reasons for the indication of allowable subject matter: The prior art, taken alone or in combination, fails to teach or to fairly suggest *in combination*,

the steps or structure for detecting the output *power*, detecting the input *power*, and determining a diffraction efficiency, as recited in claims 2, 3, 9, 10, 43 – 45, and 56 - 58;

the steps or structure for detecting the output *power*, and monitoring for stability, as variously recited in claims 4, 11, 42, 48, 55, and 61;

the apparatus wherein the second polarization differs from the first polarization

by a "small" rotation, or the step of causing this to be the case, as variously recited in

claims 7, 14, 39, 40, 52, and 52; or

the steps or structure for detecting the output power, and monitoring for a

termination condition, as variously recited in claims 36, 41, 47, 54, and 60.

Response to Amendment

Applicant's amendment is sufficient in overcoming the previous rejection of claim

12 under 35 U.S.C. §112, second paragraph.

Applicant's remarks concerning the rejection of claims 1, 5, 6, 8, 12, and 13 have

been fully considered, but are not found persuasive. Applicant's remark that "the data

beam" occurs for recording a hologram and for "measuring an offset component in an

output arm of the data beam" apparently seeks to ascribe particular meanings to "the

data beam" and to "an output arm of the data beam", whereas, in light of the

specification, these expressions are not so limited. For example, at Page 3 (lines 19 -

23) of the instant specification, the expression "data beam" also describes the data

beam as it is read out of the hologram using a substantial duplicate of the reference

beam. This read-out "data beam" is also described as comprising "an output arm of the

data beam". It is clear from Page 9 (paragraph starting with line 4) that an "output arm

of the data path" is active even when the input arm of the data path is not.

Applicant would construe the expression "an output arm of the data beam"

[emphasis added] to mean only an output arm of the said-same data beam used to

record the hologram. However, in light of the specification, the examiner believes that one of ordinary skill would not necessarily be lead to this inference. In the disclosed method, multiple holograms may be recorded in the "holographic medium". Noting the order of steps recited in claims 1 and 37, and even considering the preamble of the claim, one of ordinary skill would not necessarily infer that "the diffraction" monitored during recording of one hologram is the diffraction of the hologram being recorded. Rather, the diffraction monitored could be the diffraction of one of the pre-recorded alignment holograms; while the "offset component" measured could be the offset component in the last hologram recorded. The language of the claims does not necessarily tie the "measuring of an offset component" to the preambular recitation of "monitoring diffraction" nor does it necessarily tie the "measuring" to the hologram as it is being recorded.

In order to distinguish apparatus claims 8 and 50 over the prior art, Applicant would rely upon the recitations of the polarizing beam splitter as being "for separating an offset component from an output arm of the data beam" and of the detector as being "for measuring the offset component". However, the examiner finds that the beam splitter and detector of the prior art apparatus are arranged in such a manner as to be clearly capable of such use. The manner of operating the apparatus, and similarly, the intended use of these components during operation of the apparatus, fails to distinguish the apparatus *itself*, since the structures of the claimed apparatus and the prior art are quite apparently the same.

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Even assuming, in arguendo, that Applicant's proposed claim construction is the only reasonable construction, then it should be noted that the offset component of FUJI

XEROX is inherently present during the step of recording the second (polarization-

modulated) hologram of data. See for example, the method discussed in paragraphs

[0044] - [0047] of the reference.

Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Examiner Juba whose telephone number is (571) 272-2314. The examiner can normally be reached on Mon.-Fri. 9 - 5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Mr. Drew Dunn whose number is (571) 272-2312 and who can be reached on Mon.- Thu., 9-5.

The centralized fax phone number for the organization where this application or proceeding is assigned is (703) 872-9306 for *all* communications.

UOHN JUBA, JR. PRIMARY EXAMINER
Art Unit 2872

June 21, 2004